



Docket No. 04522/00018

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**APPLICANT:** Wikiel, et al. **EXAMINER:** Unknown  
**SERIAL NO.** 10/621,079 **GROUP:**  
**FILED:** 16 July 2003  
**FOR:** Method and Apparatus for Real Time Monitoring of  
Electroplating Bath Performance and Early Fault Detection

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT**

In accordance with the provisions of 37 C.F.R. §§1.56 and 1.97, Applicant herewith submits the publications and/or patents shown on the attached form PTO-1449, for consideration by the Examiner in connection with the examination of the above-identified patent application.

**REMARKS**

In accordance with the provisions of 37 C.F.R. §1.97, this statement is being filed (CHECK ONE):

- ☒ (1) within three (3) months of the **Filing Date** or before the mailing date of the **First Office Action** on the merits; or
- ☐ (2) after the period defined in (1) but before the mailing date of a **Final Rejection** or **Notice of Allowance**, and the requisite Certification or fee under Rule 1.17(p), is included herein; or
- ☐ (3) after the mailing date of a **Final Rejection** or **Notice of Allowance** but before the payment of the **Issue Fee**, and the requisite Certification and fee are included herein.

It is respectfully requested that each of the documents shown on the attached form(s) PTO-1449 be made of record in this application. Copies of these documents (CHECK ONE):

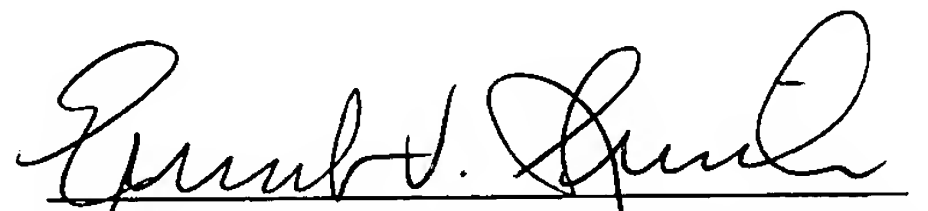
  X   are enclosed herewith; or  
       are in the file of related application Serial No., filed and are thus not being resubmitted herein.

Early examination and allowance of the present application are respectfully solicited.

**FEE AUTHORIZATION**

Should any fee associated with the submission of this paper not be attached hereto as a check, the Commissioner is authorized to charge the missing fee to our Deposit Account, No. 19-0733. Any overpayments should be credited to said Deposit Account.

Respectfully submitted,

  
Ernest V. Linek (Reg. No. 29,822)  
Attorney for Applicant  
BANNER & WITCOFF, LTD.  
28 State Street, 28<sup>th</sup> Floor  
Boston, MA 02109-1775  
(617) 720-9600

Date: 05 September 2003



## INFORMATION DISCLOSURE CITATION

Page 1 of 1

Applicant(s): Wikiel, et al.

Filing Date: July 16, 2003

Group:

## NON PATENT LITERATURE DOCUMENTS

(Include the name of the Author, (IN CAPITAL LETTERS), title of the Article (when appropriate), title of the item, date, page(s), volume issue number(s), publisher, city and/or country where published.)

AA	DIETZ, K., "Fine Lines in High Yield (Part LIII): Organic Additives in Copper Plating Baths (Part II)", CircuTree, 13(3), 2000, 54.
AB	MOFFAT, T. P., et al. "Superconformal Electrodeposition of Copper in 500-90 nm Features", Journal of the Electrochemical Society, 147 (12), 4524-4535, 2000.
AC	MOFFAT, T. P., et al. "Superconformal Electrodeposition of Copper", Electrochemical and Solid-State Letters, 4 (4), C26-C29, 2001.
AD	MOFFAT, T. P., et al. "Superconformal Electrodeposition in Sumbicron Features", Phys. Rev. Lett., 87, 2001, 16102.
AE	JOSELL, D., et al. "A Simple Equation for Predicting Superconformal Electrodeposition in Sumbmicrometer Trenches", Journal of the Electrochemical Society, 148 (12), C767-C773, 2001.
AF	DIETZ, K., "Fine Lines in High Yield (Part LIV): Organic Additives in Copper Plating Baths (Part 1a)", CircuTree, 13(2), 2000, 22.
AG	SHAH, et al., "Combination of the Mahalanobis Distance and Residual Variance Pattern Recognition Techniques for Classification of Near-Infrared Reflectance Spectra", Anal. Chem., 1990, 62, 465-470.

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant. \*\*Copies of references not provided at the time of this submission.